

1. Scope

This specification is applied to Multilayer Ceramic Chip Capacitor(MLCC) for use in electric equipment for the voltage is ranging from 4V to 50V.

The series suitable for general electrics circuit, telecommunications, personal computers and peripheral, power circuit and mobile application. (This product is compliant with the RoHS & HF.)

2. Parts Number Code



(1)Product

Product Code	
С	Multilayer Ceramic Chip Capacitor

(2)Chip Size

` /	
Code	LengthxWidth unit : mm(inch)
0201	0.60× 0.30 (.024× .011)
0402	1.00× 0.50 (.039× .020)
0603	1.60× 0.80 (.063× .031)
0805	2.00× 1.25 (.079× .049)
1206	3.20× 1.60 (.126× .063)
1210	3.20× 2.50 (.126× .098)
1808	4.60× 2.00 (.181× .079)
1812	4.60× 3.20 (.181× .125)
1825	4.60× 6.35 (.181× .250)
2208	5.70× 2.00 (.220× .197)
2211	5.70× 2.80 (.220× .110)
2220	5.70× 5.00 (.220× .197)
2225	5.70× 6.35 (.220× .250)

(3)Temperature Characteristics

Code	Temperature	Temperature	Temperature
	Characteristic	Range	Coefficient
N	NPO	-55°C ~+125°C	30 ppm/℃
X	X7R	-55°C~+125°C	± 15%
В	X5R	-55°C~+85°C	± 15%
R	X7S	-55°C~+125°C	± 22%
S	X6S	-55°C ~+105°C	± 22%
D	X5S	-55°C ~+85°C	± 22%
Υ	Y5V	-30°C~+85°C	+22/-82%
Z	Z5U	+10°C~+85°C	+22/-56%
Е	Y5U	-30°℃~+85°℃	+22/-56%

(4)Canacitance

(4)Capacitance	unit :pico farads(pF)
Code	Nominal Capacitance (pF)
5R0	5.0
120	12.0
151	150.0
222	2,200.0
473	47,000.0
474	470,000.0
105	1,000,000.0
106	10,000,000.0

*. If there is a decimal point, it shall be expressed by an English capital letter R

(5) Capacitance Tolerance

Code	Tolerance	Nominal Capacitance
В	± 0.10 pF	Less Than 10 pF
С	± 0.25 pF	(Include 10 pF)
D	± 0.50 pF	
Е	± 1.00 pF	
F	± 1.00 %	More Than 10 pF
G	± 2.00 %	_
J	± 5.00 %	
K	± 10.0 %	
М	± 20.0 %	_
Z	+80/-20 %	

(6)Rated Voltage

` '	9
Code	Rated Voltage (Vdc)
004	4
007	6.3
010	10
016	16
025	25
035	35
050	50

(7)Tapping

Туре				
Tape & Reel				
Bulk				



3. Nominal Capacitance and Tolerance

3.1 Standard Combination of Nominal Capacitance and Tolerance

Class	Characteristic	Tolera	ance	Nominal Capacitance
I	NPO	Less Then 10 pF	B (± 0.10 pF)	0.5,1,1.5,2,2.5,3
			C (± 0.25 pF)	0.5,1,1.5,2,2.5,3,3.5,4,4.5,5
			D (± 0.50 pF)	5,6,7,8,9,10
			E (± 1.00 pF)	6,7,8,9,10
		More Than 10 pF	F (±1.00 %)	E-12, E-24 series
			G (±2.00 %)	
			J (± 5.00 %)	
			K (± 10.0 %)	
П	X7R/ X7S/ X5R	K (± 10.0 %),	M (± 20.0 %)	E-3, E-6 series
	X6S/ X5S			
	Y5V	M (± 20.0 %), Z	Z(+80/-20 %)	E- 3 series
	Z5U			
	Y5U			

3.2 E series(standard Number)

Standard No.		Application Capacitance										
E- 3	1.0			2.2			4.7					
E- 6	1	.0	1	.5	2	.2	3	.3	4	.7	6.	.8
E-12	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
E-24	1.0	1.2	1.5	1.8	2.2	2.7	3.3	3.9	4.7	5.6	6.8	8.2
	1.1	1.3	1.6	2.0	2.4	3.0	3.6	4.3	5.1	6.2	7.5	9.1

4. Operation Temperature Range

_	_		
Class	Characteristic	Temperature Range	Reference Temp.
I	NPO (N)	-55℃ ~ +125℃	25 ℃
П	X7R (X)	-55℃ ~ +125℃	25 ℃
	X7S (R)	-55°C ~ +125°C	25 ℃
	X5R (B)	-55°C ~ +85°C	25 ℃
	X5S (D)	-55℃ ~ +85℃	25 ℃
	X6S (S)	-55°C ~ +105°C	25 ℃
	Y5V (Y)	-30℃ ~ +85℃	25 ℃
	Z5U (Z)	+10°C ~ +85°C	25 ℃
	Y5U (E)	-30℃ ~ +85℃	25 ℃
	Other	-25℃ ~ +85℃	25 ℃

5. Storage Condition

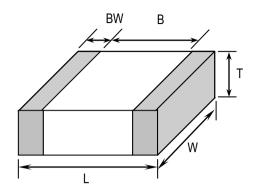
Storage Temperature : 5 to 40° C Relative Humidity : 20 to 70 % Storage Time : 12 months max.

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6. Dimensions

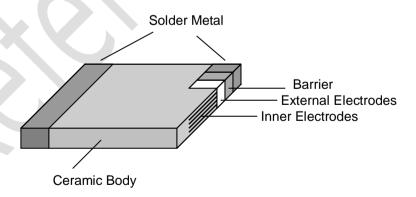
6.1 Configuration and Dimension:



Unit:mm

TYPE	L	W	T (max)	B (min)	BW (min)
0201	0.60 ± 0.03	0.30 ± 0.03	0.33	0.20	0.10
0402	1.00± 0.05	0.50 ± 0.05	0.55	0.30	0.15
0603	1.60± 0.10	0.80± 0.10	1.00	0.40	0.15
0805	2.00± 0.20	1.25± 0.20	1.45	0.70	0.20
1206	3.20 ± 0.30	1.60± 0.20	1.80	1.50	0.30
1210	3.20 ± 0.30	2.50± 0.20	2.70	1.60	0.30
1808	4.60± 0.30	2.00± 0.20	2.20	2.50	0.30
1812	4.60± 0.30	3.20 ± 0.30	3.00	2.50	0.30
1825	4.60± 0.30	6.35± 0.40	2.60	2.50	0.30
2208	5.70± 0.40	2.00± 0.20	2.20	3.50	0.30
2211	5.70± 0.40	2.80± 0.40	3.00	3.50	0.30
2220	5.70± 0.40	5.00± 0.40	3.00	3.50	0.30
2225	5.70± 0.40	6.35± 0.40	3.00	3.50	0.30

6.2 Termination Type:





7. Performance

No.	lte	em	Specification Test Condition
1	Vis	ual	No abnormal exterior appearance Visual Inspection
2	Dime	nsion	See Page 3 Visual Inspection
3		ation stance	10,000MΩ or 500/C Ω whichever is smaller for rated voltage>10V and greater 100/C Ω for rated voltage≤10V. Applied Voltage: Rated Voltage Charge Time: 60±5 sec. Charge-Discharge current shall be less than 50mA current.
4	Capac	citance	Within The Specified Tolerance Class I:
5	Q	Class	More Than 30pF : Q≥1000 Char Frequency Voltage
		I	30pF & Below: Q≥ 400+20C
			(C : Capacitance , pF) C>1000pF 1KHz±10%
	Tanδ	Class	X7R/X7S/X6S/X5R/X5S: shell meet the Class II :
		П	value in table 1 Char Frequency Voltage
			Y5V/Y5U/Z5U : 0.2 max. C≦10uF 1KHz±10% *1.0±0.2Vrms
			or 0.5±0.2Vrms
			C>10uF 120Hz±20% 0.5±0.2Vrms Perform a heat temperature at 150±5℃ for 30min
			then place room temp. for 24±2hr.
			* Depend on the individual parts.
6		anding	No dielectric breakdown or mechanical 250% of the rated voltage for 1~5 sec.
	Volt	tage	breakdown charge/discharge Current is less than 50mA.
7	Temperatur	e Class I	Char. Temp. Range Cap. Change(%) Class I
	Capacitance		Char. lemp. Range Cap. Change(%) Class I : $ 100\% $
	Coefficient		Char. Temp. Range Cap. Change(%)
		П	X7R -55°C ~+125°C ± 15%
			X7S -55°C ~+125°C ± 22% Class II :
			X6S -55° -+105° + 22% C2−C1 ×100%
			X5R -55°C ~+85°C ±15% C1
			X5S -55° C $\sim +85^{\circ}$ C $\pm 22\%$ T1: Standard Temperature(25 $^{\circ}$ C)
			Y5V -30°C ~+85°C +22% ~-82% T2: Test Temperature
			Y5U -30°C ~+85°C +22% ~-56% C1:Capacitance At Standard Temperature(25°C)
			Z5U +10°C~+85°C +22%~-56% C2: Capacitance At Test Temperature (T2)
	A -II :	Otro or orth	0.2Vrms shall be applied.
8		Strength	No indication of peeling shall occur on the terminal electrode. Pull force shall be applied for 10 ± 1 second. $\leq 06035N (= 0.5 \text{ Kg} \cdot \text{f})$
	Or rem	nination	>060310N(= 0.5 Kg·f)
			> 55000 1514(: 1.5 Hg 1)
			N·f
9		Appear-	No mechanical damage or capacitance The board shall be bend 1.0mm with a rate of 1.0
		ance	change more than the following table. mm/sec.
	Flexure	C-Meter	Capacitance Change Bending
	of Substrate		Char. Cap. Change
			$NPO(N) \le \pm 5.0\%$ of initial value C Meter
			X7R (X)
			A73 (R)
			$\times 6S (S)$ $\leq \pm 12.5\%$ of initial value
			X5R (B)
			$\begin{array}{c c} X5S & (D) \\ \hline Y5V & (Y) & \leq \pm 30.0\% & \text{of initial value} \end{array}$
			Y5U (E)
			Z5U (Z)



MULTILAYER CERAMIC CHIP CAPACITORS

No.	Ite	m	Specification		Test Condition		
10	Solder	ability	More than 90% of the terminal surface is to be soldered newly, so metal part does not come out or dissolve.		Solder Temperature : 245± 5°C Dip Time : 5 ± 0.5sec Immersing Speed : 25±10% mm/s Solder : Lead Free Solder Flux :Rosin Preheat : At 80~120 °C for 10~30sec.		
11	Resistance To Soldering Heat	Appearance Capacitance Q Class I Tano Class II Insulation Resistance	No mechanical damage shall occur. Class I Within ± 2.5% or ± 0.25pF whichever is larger of initial value X7R/X7S/X6S ≤ ±7.5% of initial value X5R/X5S Y5V/Y5U/Z5U ≤ ±20% of initial value To satisfy the specified initial value X7R/X7S/X6S/X5R/X5S: shell meet the value in table 1 Y5V/Y5U/Z5U : 0.2 max. To satisfy the specified initial value		Class II capacitor shall be set for 48±4 hours at room temperature after one hour heat treatment at 150 ± 0/-10°C before initial measure. Preheat: at 150± 10°C for 60~120sec. Dip: solder temperature of 260± 5°C Dip Time: 10 ± 1sec. Immersing Speed: 25±10% mm/s Flux: Rosin Measure at room temperature after cooling for Class I: 24 ± 2 Hours Class II: 48 ± 4 Hours		
12	Tempera ture Cycle	Appearance Capacitance Q Class I Tanō Class II	No mechanical dame Class I (NPO) X7R/X7S/X6S X5R/X5S Y5V/Y5U/Z5U To satisfy the specific table 1 Y5V/Y5U/Z5U: 0.2 in To satisfy the specific table 1 Y5V/Y5U/Z5U: 0.2 in To satisfy the specific table 1	Within ± 2.5% or ± 0.25pF whichever is larger of initial value ≤ ±7.5% of initial value ≤ ±20% of initial value ed initial value X5S: shell meet the value in max.	Class II capacitor shall be set for 48±4 hours at room temperature after one hour heat treatment at 150 +0/-10°C before initial measure. Capacitor shall be subjected to five cycles of the temperature cycle as following: Step Temp.(°C) Time(min) 1 Min Rated Temp. +0/-3 30 2 25 3 Max Rated Temp. +3/-0 30 4 25 3 Measure at room temperature after cooling for Class I: 24 ± 2 Hours Class II: 48 ± 4 Hours		
13	Humidity	Appearance Capacitance Q Class I Tanō Class II Insulation Resistance	table 1 Y5V/Y5U/Z5U : 0.4 I 1000MΩ or 50/C Ω	Cap. Change Within ± 5.0% or ± 0.5pF whichever is larger of initial value ≤ ±12.5% of initial value ≤ ±30% of initial value 350 3+2.5C 200+10C X5S: shell meet the value in	Class II capacitor shall be set for 48± 4 hours at room temperature after one hour heat treatment at 150 +0/-10 °C before initial measure. Temperature: 40± 2°C Relative Humidity: 90 ~ 95%RH Test Time: 500 +12/-0Hr Measure at room temperature after cooling for Class I: 24 ± 2 Hours Class II: 48 ± 4 Hours		

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MULTILAYER CERAMIC CHIP CAPACITORS

No.	Ite	m	Specification		Test Condition
14	Humidity Load	Appear- ance	No mechanical dama	ge shall occur.	Class ☐ capacitors applied DC voltage of the rated voltage is applied for one hour at maximum
		Capacit-	Characteristic	Cap. Change	operation temperature ± 3°C then shall be set for
		ance		Within ± 7.5% or ± 0.75pF	48± 4 hours at room temperature and the initial
			(NPO)	whichever is larger of	measurement shall be conducted.
				initial value	Applied Voltage :Rated Voltage
				≤ ±12.5% of initial value	Temperature : 40± 2°C
			X5R/X5S		Relative Humidity: 90 ~ 95%RH
				≤ ±30% of initial value	Test Time: 500 +12/-0Hr
		Q	30pF & Over : Q ≥3		Current Applied : 50 mA Max.
		Class I	10 to 30pF : Q ≥ 275+ 30pF & Below: Q ≥ 20		Measure at room temperature after cooling for
			· ·		Class T. O4 . O Haves
		Tanδ		5S: shell meet the value in	Class II : 48 ± 4 Hours
		Class II	table 1 Y5V/Y5U/Z5U: 0.4 m	nav	
		Insulation		hichever is smaller for	
		Resistance		nd greater 5/C Ω for rated	
		110313141100	voltage≦10V.	(C in Farad)	
15	High	Appear-	No mechanical dama	ge shall occur.	The capacitors applied DC testing voltage is
	Temperature				applied for one hour at maximum operation
	Load	Capacit-	Characteristic		temperature ±3°C then shell be set for 48± 4
	(Life Test)	ance	Class I	·	hours at room temperature and the initial
			(NPO)	whichever is larger of initial value	measurement shall be conducted. Applied Voltage: Rated Voltage
			X7R/X7S/X6S	≤ ±12.5% of initial value	However:
			X5R/X5S		The class I applied voltage 200% of rated
			Y5V/Y5U/Z5U	≤ ±30% of initial value	voltage.
		Q	30pF & Over : Q ≥3		Temperature: max. operation temperature
		Class I	10 to 30pF : Q ≥ 275+		Test Time: 1000 +48/-0 Hr
			30pF & Below: Q≥20		Current Applied : 50mA Max
		Tanδ		5S: shell meet the value in	Measure at room temperature after cooling for
		Class II	table 1		Class I: 24 ± 2 Hours
		Insulation	Y5V/Y5U/Z5U : 0.4 m	whichever is smaller for	Class II : 48 ± 4 Hours
		Resistance	rated voltage>10V an	d greater 10/C Ω for rated	
	1	rtesistance	voltage≦10V.	(C in Farad)	
16	Vibration	Appear-	No mechanical dama	ge shall occur	Solder the capacitor on P.C. board.
		ance			Vibrate the capacitor with amplitude of
		Capacit-	Within the specified to	olerance	1.5mm P-P changing the frequencies
		ance			from 10Hz to 55Hz and back to 10Hz
		Q	To satisfy the specifie	ed initial value	in about 1 min.
		Class I	V7D		Reneat this for 2 hours each in 3 perpendicular
		Tanδ		55: snell meet the value in	Repeat this for 2 hours each in 3 perpendicular directions.
		Class II	table 1		
			Y5V/Y5U/Z5U: 0.2 m	IdX.	

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Table 1

emp char: X7R,X7S,X6S,X5R,X5S

	Datastication	0		δ (MAX)
	Rated voltage	Capacitance Range	5. Initial16. Vibration11. Resistance to solder heat	13.Humidity 14.Humidity loading 15.High temperature loading
			12.Temperature cycle	
0201	DC 6.3V	C≦0.01uF	10.0%	20.0%
		C=0.1uF	15.0%	25.0%
	DC 10V	C≦0.01uF	10.0%	20.0%
	DC 16V	C≦3.3nF	10.0%	20.0%
	DC 25V	C≦2.2nF	10.0%	20.0%
	DC 50V	C≦1nF	10.0%	20.0%
0402	DC 6.3V	C≦0.22uF	10.0%	20.0%
		C≦2.2uF	15.0%	25.0%
	DC 10V	C≦0.1uF	10.0%	20.0%
		C≦2.2uF	15.0%	25.0%
	DC 16V	C≦1.0uF	15.0%	25.0%
	DC 25V	C≦0.47uF	15.0%	20.0%
0603	DC 50V	C≦3.9nF	10.0%	20.0%
0603	DC 6.3V	C<4.7uF	10.0%	20.0%
	DC 40\/	C≤10uF	15.0%	25.0%
	DC 10V	C<4.7uF C≦10uF	10.0% 15.0%	20.0%
	DC 16V	C≦ 10uF C≦2.2uF	10.0%	20.0%
	DC 16V DC 25V	C≦2.2uF C≦1.0uF	10.0%	20.0%
	DC 25V DC 50V	C≦1.0uF C≦0.1uF	10.0%	20.0%
	DC 6.3V	C<10uF	10.0%	20.0%
0805	DC 0.5V	C≦22uF	15.0%	25.0%
	DC 10V	C≦4.7uF	10.0%	20.0%
	20.00	C≦22uF	15.0%	25.0%
	DC 16V	C≦4.7uF	10.0%	20.0%
		C≦10uF	15.0%	25.0%
	DC 25V	C≦4.7uF	10.0%	20.0%
		C=10uF	10.0%	20.0%
	DC 50V	C≦1.0uF	10.0%	20.0%
		C=2.2uF	10.0%	20.0%
1206	DC 6.3V	C<10uF	10.0%	20.0%
1200		C≦100uF	15.0%	25.0%
	DC 10V	C≦47uF	10.0%	20.0%
	DC 16V	C≦22uF	10.0%	20.0%
	DC 25V	C≦10uF	10.0%	20.0%
		10uF <c≦22uf< td=""><td>15.0%</td><td>25.0%</td></c≦22uf<>	15.0%	25.0%
	DC 35V	C≦10uF	10.0%	20.0%
	DC 50V	C≦4.7uF	10.0%	20.0%
		C=10uF	12.5%	25.0%
1210	DC 6.3V	C≦47uF	10.0%	20.0%
		47uF <c≦100uf< td=""><td>15.0%</td><td>25.0%</td></c≦100uf<>	15.0%	25.0%
	DC 10V	C≦22uF	10.0%	20.0%
		22uF <c≦47uf< td=""><td>15.0%</td><td>25.0%</td></c≦47uf<>	15.0%	25.0%
	20.401/	C=100uF	10.0%	20.0%
	DC 16V	C≦10uF	10.0%	20.0%
	DO 051/	10uF <c≦47uf< td=""><td>15.0%</td><td>25.0%</td></c≦47uf<>	15.0%	25.0%
	DC 25V	C≦10uF	10.0%	20.0%
		10uF <c≦22uf< td=""><td>15.0%</td><td>25.0%</td></c≦22uf<>	15.0%	25.0%
	DC 35V	C<4.7uF	10.0%	20.0%
		C≦10uF	10.0%	20.0%
	DC 50V	C≦10uF	10.0%	20.0%
4040	DC 6.3V	4	10.0%	20.0%
1812	DC 10V	4	10.0%	20.0%
	DC 16V DC 25V	All Capacitance	10.0% 10.0%	20.0% 20.0%
	DC 25V DC 35V	+	10.0%	20.0%
	DC 50V	†	10.0%	20.0%
2220	DC 35V	All Capacitance	10.0%	20.0%



Fig.1
P.C. Board for Bending Strength Test

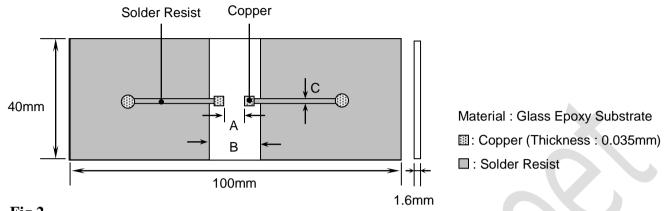
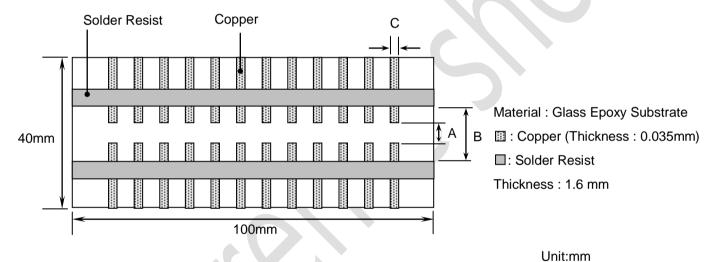


Fig.2 Test Substrate



Type	А	В	С
0201	0.2	0.9	0.4
0402	0.5	1.5	0.6
0603	1.0	3.0	1.0
0805	1.2	4.0	1.6
1206	2.2	5.0	2.0
1210	2.2	5.0	2.9
1808	3.5	7.0	2.5
1812	3.5	7.0	3.7
2208	4.5	8.0	2.5
2211	4.5	8.0	3.0
2220	4.5	8.0	5.6

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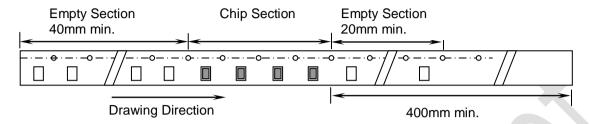


8. Packing

8.1 Bulk Packing

According to customer request.

8.2 Chip Capacitors Tape Packing



8.3 Material And Quantity

Tape	0201	0402	0603/	/0805
Material	T≦0.33mm	$T \leq 0.55 mm$	T≦0.90mm	T>0.90mm
Paper	15,000 pcs/Reel	10,000 pcs/Reel	4,000 pcs/Reel	NA
Plastic	NA	NA	NA	3,000 pcs/Reel

Tape	1206					
Material	T≦0.90mm	0.90mm <t≦1.25mm< td=""><td>T>1.25mm</td></t≦1.25mm<>	T>1.25mm			
Paper	4,000 pcs/Reel	NA	NA			
Plastic	NA	3,000 pcs/Reel	2,000 pcs/Reel			

Tape	1808/1210						
Material	T≦1.25mm	1.25mm <t≦2.40mm< td=""><td>T>2.40mm</td></t≦2.40mm<>	T>2.40mm				
Paper	NA	NA	NA				
Plastic	3000 pcs/Reel	2000 pcs/Reel	500/1,000 pcs/Reel				

Tape	1812/22	11/2220	1825	2208	
Material	T≦2.20mm	T>2.20mm	T≦2.20mm	T>2.20mm	T≦2.20mm
Paper	NA	NA	NA	NA	NA
Plastic	1000 pcs/Reel	700 pcs/Reel	700 pcs/Reel	400 pcs/Reel	1000 pcs/Reel

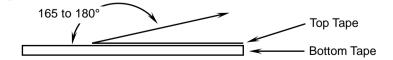
NA: Not Available

8.4 Cover Tape Reel Off Force

8.4.1 Peel-Off Force

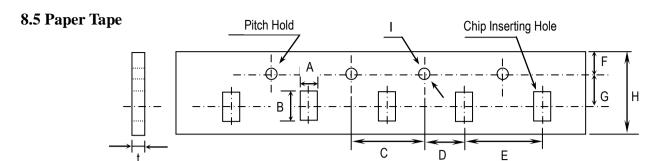
 $5 g \cdot f \leq Peel-Off Force \leq 70 g \cdot f$

8.4.2 Measure Method



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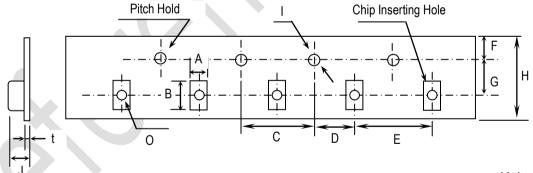


Unit:mm

TYPE	Α	В	С	D	Е
0201	0.37± 0.1	0.67± 0.1	4.00± 0.1	2.00 ± 0.05	2.00± 0.1
0402	0.61± 0.1	1.20± 0.1			
0603	1.10± 0.2	1.90± 0.2			4.00± 0.1
0805	1.50± 0.2	2.30± 0.2			
1206	1.90± 0.2	3.50± 0.2			
1210	2.90± 0.2	3.60± 0.2			

TYPE	F	G	Н	I	t
0201	1.75± 0.10	3.50 ± 0.05	8.0 ± 0.30	φ 1.50 +0.10/-0	1.10 max.
0402					
0603					
0805					
1206					
1210					

8.6 Plastic Tape



Unit:mm

Туре	А	В	С	D	Е	F
0805	1.5±0.2	2.3±0.2	4.0± 0.1	2.0± 0.05	4.0± 0.1	1.75± 0.1
1206	1.9±0.2	3.5±0.2				
1210	2.9±0.2	3.6±0.2				
1808	2.5±0.2	4.9±0.2				
1812	3.6±0.2	4.9±0.2			8.0± 0.1	
1825	6.9±0.2	4.9±0.2				
2208	2.5±0.2	6.1±0.2				
2211	3.2±0.2	6.1±0.2				
2220	5.4±0.2	6.1±0.2				
2225	6.9±0.2	6.1±0.2				

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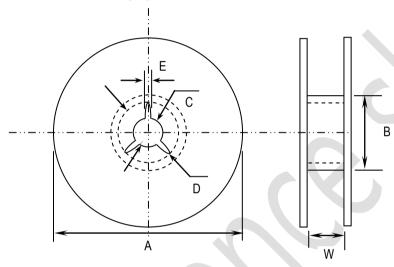


MULTILAYER CERAMIC CHIP CAPACITORS

Type	G	Н	I	J	t	0
0805	3.5± 0.05	8.0± 0.3	φ 1.5+0.1/-0	3.0 max.	0.3 max.	1.0± 0.1
1206						
1210						
1808	5.5± 0.05	12.0 ± 0.3		4.0 max.		1.5± 0.1
1812						
1825						
2208						
2211						
2220						
2225						

8.7 Reel Dimensions

Reel Material: Polystyrene



Unit:mm

Type	А	В	С	D	Е	W
0201	φ 382 max	φ 50 min	φ 13± 0.5	φ 21± 0.8	2.0±0.5	10± 0.15
0402						
0603						
0805						
1206						
1210						
1808	φ 178±0.2	φ 60±0.2				13±0.3
1812						
1825						
2208						
2211						
2220						
2225						

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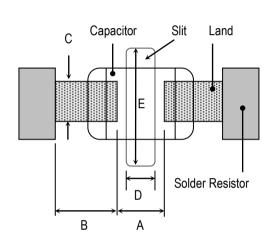
Precautionary Notes:

1. Storage

Store the capacitors where the temperature and relative humidity don't exceed 40°C and 70%RH. We recommend that the capacitors be used within 12 months from the date of manufacturing. Store the products in the original package and do not open the outer wrapped, polyethylene bag, till just before usage. If it is open, seal it as soon as possible or keep it in a desiccant with a desiccation agent.

2. Construction of Board Pattern

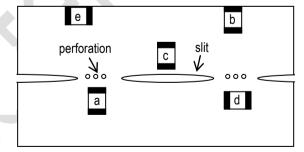
Improper circuit layout and pad/land size may cause excessive or not enough solder amount on the PC board. Not enough solder may create weak joint, and excessive solder may increase the potential of mechanical or thermal cracks on the ceramic capacitor. Therefore we recommend the land size to be as shown in the following table: 2.1 Size and recommend land dimensions for reflow soldering



EIA Code	Chip (mm)		Land (mm)				
LIA Code	L	W	Α	В	С	D	Е
0201	0.60	0.30	0.2~0.3	0.2~0.4	0.2~0.4		
0402	1.00	0.50	0.3~0.5	0.3~0.5	0.4~0.6		-
0603	1.60	0.80	0.4~0.6	0.6~0.7	0.6~0.8		
0805	2.00	1.25	0.7~0.9	0.6~0.8	0.8~1.1		
1206	3.20	1.60	2.2~2.4	0.8~0.9	1.0~1.4	1.0~2.0	3.2~3.7
1210	3.20	2.50	2.2~2.4	1.0~1.2	1.8~2.3	1.0~2.0	4.1~4.6
1808	4.60	2.00	2.8~3.4	1.8~2.0	1.5~1.8	1.0~2.8	3.6~4.1
1812	4.60	3.20	2.8~3.4	1.8~2.0	2.3~3.0	1.0~2.8	4.8~5.3
1825	4.60	6.35	2.8~3.4	1.8~2.0	5.1~5.8	1.0~4.0	7.1~8.3
2208	5.70	2.00	4.0~4.6	2.0~2.2	1.5~1.8	1.0~4.0	3.6~4.1
2211	5.70	2.80	4.0~4.6	2.0~2.2	2.0~2.6	1.0~4.0	4.4~4.9
2220	5.70	5.00	4.0~4.6	2.0~2.2	3.5~4.8	1.0~4.0	6.6~7.1
2225	5.70	6.35	4.0~4.6	2.0~2.2	5.1~5.8	1.0~4.0	7.1~8.3

2.2 Mechanical strength varies according to location of chip capacitors on the P.C. board.
Design layout of components on the PC board such a way to minimize the stress imposed on the components, upon flexure of the boards in depanelization or other processes.

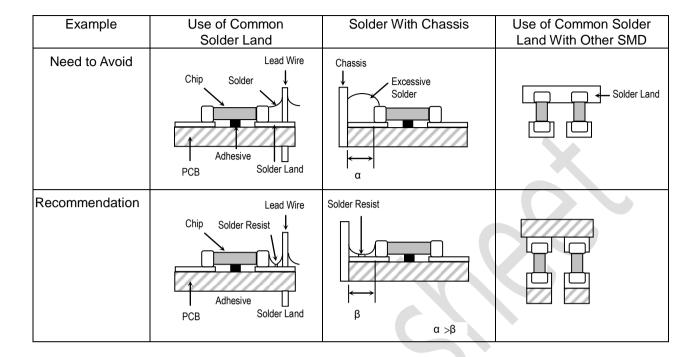
Component layout close to the edge of the board or the "depanelization line" is not recommended. Susceptibility to stress is in the order of: a>b>c and d>e



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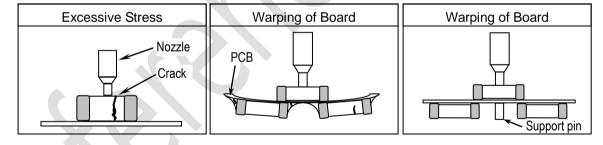
2.3 Layout Recommendation



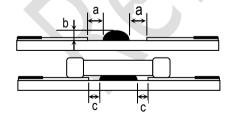
3. Mounting

3.1 Sometimes crack is caused by the impact load due to suction nozzle in pick and place operation. In pick and place operation, if the low dead point is too low, excessive stress is applied to component. This may cause cracks in the ceramic capacitor, therefore it is required to move low dead point of a suction nozzle to the

cause cracks in the ceramic capacitor, therefore it is required to move low dead point of a suction nozzle to the higher level to minimize the board warp age and stress on the components. Nozzle pressure is typically adjusted to 1N to 3N (static load) during the pick and place operation.



3.2 Amount of Adhesive



Example: 0805 & 1206

а	0.2mm min.
b	70 ~ 100 μm
С	Do not touch the solder land

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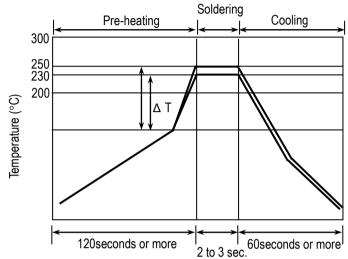


4. Soldering

4.1. Wave Soldering

Most of components are wave soldered with solder at 230 to 250°C. Adequate care must be taken to prevent the potential of thermal cracks on the ceramic capacitors. Refer to the soldering methods below for optimum soldering benefits.

Recommend flow soldering temperature Profile



Soldering Method	Change in Temp.(°ℂ)		
1206 and Under	Δ T ≤ 100~130 max.		

To optimize the result of soldering, proper preheating is essential:

- 1) Preheat temperature is too low
 - a. Flux flows to easily
 - b. Possibility of thermal cracks
- 2) Preheat temperature is too high
 - a. Flux deteriorates even when oxide film is removed
 - b. Causes warping of circuit board
 - c. Loss of reliability in chip and other components

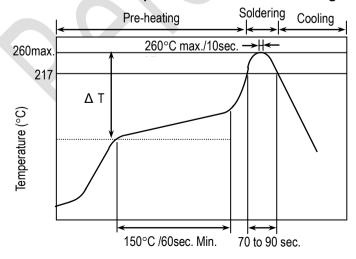
Cooling Condition:

Natural cooling using air is recommended. If the chips are dipped into a solvent for cleaning, the temperature difference (Δ T) between the solvent and the chips must be less than 100°C.

4.2 Reflow Soldering

Preheat and gradual increase in temperature to the reflow temperature is recommended to decrease the potential of thermal crack on the components. The recommended heating rate depends on the size of component, however it should not exceed 3°C/Sec.

Recommend reflow profile for Lead-Free soldering temperature Profile (MIL-STD-202G #210F)



The cycles of soldering : Twice (max.)

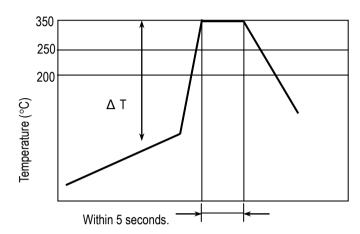
Soldering Method	Change in Temp.(°C)
1206 and Under	Δ T \leq 190 $^{\circ}$ C
1210 and Over	Δ T ≦ 130 °C

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4.3 Hand Soldering

Sudden temperature change in components, results in a temperature gradient recommended in the following table, and therefore may cause internal thermal cracks in the components. In general a hand soldering method is not recommended unless proper preheating and handling practices have been taken. Care must also be taken not to touch the ceramic body of the capacitor with the tip of solder Iron.



Soldering Method	Change in Temp.(°C)
1206 and Under	Δ T \leq 150 $^{\circ}$ C
1210 and Over	Δ T \leq 130 $^{\circ}$ C

How to Solder Repair by Solder Iron

1) Selection of the soldering iron tip

The required temperature of solder iron for any type of repair depends on the type of the tip, the substrate material, and the solder land size.

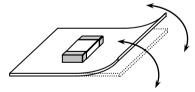
- 2) recommended solder iron condition
 - a.) Preheating Condition: Board and components should be preheated sufficiently at 150°C or over, and soldering should be conducted with soldering iron as boards and components are maintained at sufficient temperatures.
 - b.) Soldering iron power shall not exceed 30 W.
 - c.) Soldering iron tip diameter shall not exceed 3mm.
 - d.) Temperature of iron tip shall not exceed 350°C to perform the process within 5 seconds. (refer to MIL-STD-202G)
 - f.) Do not touch the ceramic body with the tip of solder iron. Direct contact of the soldering iron tip to ceramic body may cause thermal cracks.
 - g.) After soldering operation, let the products cool down gradually in the room temperature.

5. Handling after chip mounted

5.1 Proper handling is recommended, since excessive bending and twist of the board, depends on the orientation of the chip on the board, may induce mechanical stress and cause internal crack in the capacitor.

Bending _

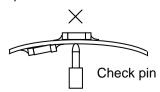
Higher potential of crack

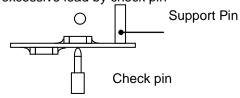


Lower potential of crack

Twist

5.2 There is a potential of crack if board is warped due to excessive load by check pin





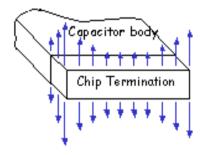
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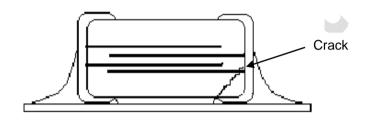


- 5.3 Mechanical stress due to warping and torsion.
 - (a) Crack occurrence ratio will be increased by manual separation.
 - (b) Crack occurrence ratio will be increased by tensile force, rather than compressive force.



Capacitor Stress Analysis



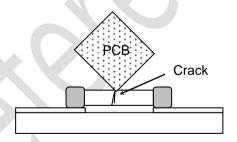


6. Handling of Loose Chip Capacitor

6.1 If dropped the chip capacitor may crack.



6.2 In piling and stacking of the P.C. boards after mounting for storage or handling, the corner of the P.C. board may hit the chip capacitor mounted on another board to cause crack.



7. Safekeeping condition and period

For safekeeping of the products, we recommend to keep the storage temperature between +5 to +40°C and under humidity of 20 to 70% RH. The shelf life of capacitors is 12 months.

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单击下面可查看定价,库存,交付和生命周期等信息

>>Holy Stone(禾伸堂)